

Notice of References Cited

Application/Control No.

~~00/000,000~~ 09/654,253Applicant(s)/Patent Under
Reexamination
<Unknown>

Examiner

Morella I Rosales-Hanner

Art Unit

2123

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,867,399	02-1999	Rostoker et al.	354/489
	C	US-			
	D	US-			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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	U	Teresa Serrano-Gotarredona and Bernabe Linares-Barranco, "A New Five-Parameter MOS Transistor Mismatch Model", IEEE Electron device Letters, Vol 21, No. 1, Jan 2000, Pgs 37 - 39.
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